



DATE: 14th April, 2010

PCN #: 2001

PCN Title: ZLLS1000TA, ZLLS2000TA, and ZLLS410TA Datasheet
Specification Change

Dear Customer:

This is an announcement of change(s) to products that are currently being offered by Diodes Incorporated.

We kindly request that you acknowledge receipt of this notification immediately upon receipt. If you require samples for evaluation purposes, please let us know as soon as possible. Please refer to the implementation date of this change as it is stated in the attached PCN form. Please contact your local Diodes sales representative to acknowledge receipt of this PCN and for any sample requests.

Previously agreed upon customer specific change process requirements or device specific requirements will be addressed separately.

For questions or clarification regarding this PCN, please contact your local Diodes sales representative.

Sincerely,

Diodes Incorporated PCN Team



PRODUCT CHANGE NOTICE

**PCN-2001-F
REV00**

Notification Date:	Implementation Date:	Product Family:	Change Type:	PCN #:
April 14, 2010	Immediate	Schottky Diodes	Electrical Specification	2001
TITLE				
ZLLS1000TA, ZLLS2000TA, and ZLLS410TA Datasheet Specification Change				
DESCRIPTION OF CHANGE				
Updates to the manufacturing environments have led to the necessity of an increase of specification limits for certain parameters to aid in manufacturability and capability. Differences between the previous version and the current version are high-lighted in the attached documents.				
IMPACT				
Increase in Specification Limits				
PRODUCTS AFFECTED				
ZLLS1000TA ZLLS2000TA ZLLS410TA				
WEB LINKS				
Manufacturer's Notice:	http://www.diodes.com/quality/pcns			
For More Information Contact:	http://www.diodes.com/contacts			
Data Sheet:	http://www.diodes.com/products			
DISCLAIMER				
Unless a Diodes Incorporated Sales representative is contacted in writing within 30 days of the posting of this notice, all changes described in this announcement are considered approved.				

Details of Change to ZLLS1000 Datasheet Specification

Updates to the manufacturing environments have led to the necessity to increase specification limits for certain parameters to aid manufacturability and capability.

Application:

Application testing has shown that the behavior of the ZLLS1000 version 4 in selected parameters (below) is identical to the LED typical application in Version 3.

Results using the ZXLD1366EV1 evaluation board:

- 1) 30V single LED → the diode is in blocking
- 2) 18V 4LEDs → the diode is mainly conducting

ILED [mA]	30V single LED (blocking)		18V 4LEDs (Conducting)	
	Version 4	Version 3	Version 4	Version 3
200	67.40%	67.10%	91%	91%
500	67.30%	68.20%	90.10%	90.50%
1000	60.00%	61.20%	85.27%	86.10%

Differences:

Differences between version 3 and version 4 of the ZLLS1000 datasheet are as follows:

From (Version 3):

ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	VALUE	UNIT
Schottky diode			
Continuous reverse voltage	V_R	40	V
Forward current	I_F	1.16	A
Peak repetitive forward current Rectangular pulse duty cycle	I_{FPK}	1.88	A
Non repetitive forward current	$t \leq 100\mu s$ $t \leq 10ms$	22	A
		6.4	A
Package			
Power dissipation at $T_{amb}=25^\circ C$ single die continuous	P_D	625	mW
single die measured at $t < 5$ secs		840	mW
Storage temperature range	T_{stg}	-55 to +150	$^\circ C$
Junction temperature	T_j	150	$^\circ C$

From (Version 3 cont'd):

ELECTRICAL CHARACTERISTICS (at Tamb = 25°C unless otherwise stated)

SCHOTTKY DIODE CHARACTERISTICS						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS
Reverse breakdown voltage	$V_{(BR)R}$	40			V	$I_R=500\mu A$
Forward voltage	V_F		280	310	mV	$I_F=50\text{ mA}^*$
			310	340	mV	$I_F=100\text{ mA}^*$
			355	390	mV	$I_F=250\text{mA}^*$
			405	460	mV	$I_F=500\text{mA}^*$
			450	510	mV	$I_F=750\text{mA}^*$
			490	560	mV	$I_F=1\text{A}^*$
			570	660	mV	$I_F=1.5\text{A}^*$
			475		mV	$I_F=1000\text{mA}^*, T_a = 100^\circ\text{C}$
Reverse current	I_R		11	20	μA	$V_R=30\text{V}$
			750		μA	$V_R=30\text{V}, T_a = 85^\circ\text{C}$
Diode capacitance	C_D		26		pF	$f=1\text{MHz}, V_R=30\text{V}$
Reverse recovery time	t_{rr}		4		ns	Switched from
Reverse recovery charge	Q_{rr}		335		nC	$I_F = 500\text{mA}$ to $V_R = 5.5\text{V}$ Measured @ $I_R 50\text{mA}$. $di/dt = 500\text{mA/ns}$. $R_{source} = 6\Omega; R_{load} = 10\Omega$

*Measured under pulsed conditions. Pulse width = 300 μ S. Duty Cycle \leq 2%.

To (Version 4):

Maximum Ratings @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Characteristic	Symbol	Value	Unit
Continuous Reverse Voltage	V_R	40	V
Forward Current	I_F	1.16	A
Peak Repetitive Forward Current Rectangular Pulse Duty Cycle 50% 100 μ s pulse width	I_{Fpk}	2.6	A
Non Repetitive Forward Current	$t \leq 100\mu\text{s}$	22	A
	$t \leq 10\text{ms}$	6.4	A

Thermal Characteristics

Characteristic	Symbol	Value	Unit
Power Dissipation @ $T_A = 25^\circ\text{C}$	Single Die Continuous	0.8	W
	Single Die Measured at $t < 5$ secs	1.18	W
Thermal Resistance Junction to Ambient (Note 3)	$R_{\theta JA}$	155	$^\circ\text{C/W}$
Thermal Resistance Junction to Ambient (Note 4)	$R_{\theta JA}$	106	$^\circ\text{C/W}$
Thermal Resistance Junction to Lead (Solder Point)	$R_{\theta JL}$	80	$^\circ\text{C/W}$
Storage temperature range	T_{STG}	-55 to +150	$^\circ\text{C}$
Junction temperature	T_J	150	$^\circ\text{C}$

Notes: 3. For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.
4. For a device mounted on FRB PCB measured at $t < 5$ secs.

To (Version 4 cont'd):

Electrical Characteristics @T _A = 25°C unless otherwise specified						
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
Reverse breakdown voltage	V _{(BR)R}	40	-	-	V	I _R = 500μA
Forward voltage (Note 5)	V _F	-	320	355	mV	I _F = 50mA
			335	380		I _F = 100mA
			380	425		I _F = 250mA
			410	460		I _F = 500mA
			440	510		I _F = 750mA
			470	560		I _F = 1A
			530	660		I _F = 1.5A
			430	-		I _F = 1000mA, T _A = 100°C
Reverse current	I _R	-	5	20	μA	V _R = 30V
			500	-	μA	V _R = 30V, T _A = 85°C
Diode capacitance	C _D	-	28	-	pF	f = 1MHz, V _R = 30V
Reverse recovery time	t _{rr}	-	5	-	ns	Switched from I _F = 500mA to V _R = 5.5V
Reverse recovery charge	Q _{rr}	-	350	-	nC	Measured @ I _R 50mA, di/dt = 500mA/ ns. R _{source} = 6Ω; R _{load} = 10Ω

Notes: 5. Measured under pulsed conditions. Pulse width = 300μs. Duty cycle < 2%

All graphs in version 4 have been updated to reflect revised typical performance.

Details of Change to ZLLS2000 Datasheet Specification

Updates to the manufacturing environments have led to the necessity to increase specification limits for certain parameters to aid manufacturability and capability.

A small increase in the typical performance is seen for lower currents. For operating currents from 500mA and higher, the Voltage drop across the forward bias diode is lower thus minimizing power dissipation. The reverse bias leakage is reduced by 50%. This further implies that there is a reduction in power dissipation and an increase in maximum operating temperature during significant reverse bias duty.

Application:

Application testing has shown that the behavior of the ZLLS2000 version 5 in selected parameters (below) is identical to the LED typical application in Version 4.

Results using the ZXLD1322 evaluation board:

1) Data from 2 LED @350mA with Vin @ 8V

DS version	Efficiency
Version 4	76.1%
Version 5	75.3%

Differences:

Differences between version 4 and version 5 of the ZLLS2000 datasheet are as follows:

From (Version 4):

ELECTRICAL CHARACTERISTICS (at $T_{amb} = 25^{\circ}\text{C}$ unless otherwise stated)

SCHOTTKY DIODE CHARACTERISTICS						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS
Reverse breakdown voltage	$V_{(BR)R}$	40			V	$I_R = 1\text{mA}$
Forward voltage	V_F		260	-	mV	$I_F = 50\text{mA}^*$
			290	-	mV	$I_F = 100\text{mA}^*$
			322	-	mV	$I_F = 250\text{mA}^*$
			345	370	mV	$I_F = 500\text{mA}^*$
			395	430	mV	$I_F = 1000\text{mA}^*$
			440	490	mV	$I_F = 1500\text{mA}^*$
			475	540	mV	$I_F = 2000\text{mA}^*$
			550	640	mV	$I_F = 3000\text{mA}^*$
			465			$I_F = 2000\text{mA}^*, T_A = 100^{\circ}\text{C}$
Reverse current	I_R		25	40	μA	$V_R = 30\text{V}$
			1.7		mA	$V_R = 30\text{V}, T_A = 85^{\circ}\text{C}$
Diode capacitance	C_D		65		pF	$f = 1\text{MHz}, V_R = 30\text{V}$
Reverse recovery time	t_{rr}		6		ns	Switched from $I_F = 500\text{mA}$ to $V_R = 5.5\text{V}$ Measured @ $I_R = 50\text{mA}$. $di/dt > 500\text{mA}/\text{ns}$. $R_{source} = 6\Omega; R_{load} = 10\Omega$
Reverse recovery charge	Q_{rr}		685		pC	

*Measured under pulsed conditions. Pulse width=300 μs . Duty cycle $\leq 2\%$

To (Version 5):

Electrical Characteristics @ $T_A = 25^{\circ}\text{C}$ unless otherwise specified						
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
Reverse Breakdown Voltage	$V_{(BR)R}$	40	-	-	V	$I_R = 1\text{mA}$
Forward Voltage (Note 5)	V_F		285	-	mV	$I_F = 50\text{mA}$
			305	-		$I_F = 100\text{mA}$
			335	-		$I_F = 250\text{mA}$
			365	390		$I_F = 500\text{mA}$
			403	430		$I_F = 1\text{A}$
			433	490		$I_F = 1.5\text{A}$
			461	540		$I_F = 2\text{A}$
			509	600		$I_F = 3\text{A}$
			450	-		$I_F = 2\text{A}, T_A = 100^{\circ}\text{C}$
Reverse Current	I_R	-	10	40	μA	$V_R = 30\text{V}$
		-	0.6	-	mA	$V_R = 30\text{V}, T_A = 85^{\circ}\text{C}$
Diode Capacitance	C_D	-	65	-	pF	$f = 1\text{MHz}, V_R = 30\text{V}$
Reverse Recovery Time	t_{rr}	-	6	-	ns	Switched from $I_F = 500\text{mA}$ to $V_R = 5.5\text{V}$ Measured @ $I_R = 50\text{mA}$. $di/dt = 500\text{mA}/\text{ns}$. $R_{source} = 6\Omega; R_{load} = 10\Omega$
Reverse Recovery Charge	Q_{rr}	-	685	-	nC	

Notes: 5. Measured under pulsed conditions. Pulse width = 300 μs . Duty cycle < 2%

All graphs in version 5 have been updated to reflect revised typical performance.

Details of Change to ZLLS410 Datasheet Specification

Updates to the manufacturing environments have led to the necessity to increase specification limits for certain parameters to aid manufacturability and capability.

Significant enhancements to the device performance have been made including (a) improvement to the device performance with respect to reverse bias leakage current improving reverse power, (b) an improvement in high current Vf performance over previous version of devices, (c) improvement in SOA and maximum ambient operating temperature for a wide range of duty cycle, and (d) an increase in very low current Vf performance over previous version of devices.

Differences:

Differences between version 1 and version 2 of the ZLLS410 datasheet are as follows:

From (Version 1):

Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Continuous reverse voltage	V_R	10	V
Forward current	I_F	570	mA
Peak repetitive forward current Rectangular pulse duty cycle 50%, Pulse width = 100 μ s	I_{FPK}	1.25	A
Non repetitive forward current $t \leq 100\mu$ s $t \leq 10$ ms	I_{FSM}	17 4	A
Power dissipation at $T_{amb} = 25^\circ\text{C}$			
Continuous	P_D	330	mW
$t \leq 5$ secs		390	mW
Operating and storage temperature range	T_J, T_{stg}	-55 to 150	$^\circ\text{C}$

Electrical characteristics (at $T_{amb} = 25^{\circ}\text{C}$ unless otherwise stated)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Reverse breakdown voltage	$BV_{(BR)R}$	10			V	$I_R = 200\mu\text{A}$
Forward voltage	V_F		250	290	mV	$I_F = 10\text{mA}^{(*)}$
			330	380	mV	$I_F = 100\text{mA}^{(*)}$
			535	580	mV	$I_F = 1\text{A}^{(*)}$
Reverse current	I_R		1.8	4	μA	$V_R = 5\text{V}$
			2.2	5	μA	$V_R = 8\text{V}$
			2.5	6	μA	$V_R = 10\text{V}$
				300	μA	$V_R = 8\text{V}, T_A = 85^{\circ}\text{C}$
Diode capacitance	C_D		26		pF	$f = 1\text{MHz}, V_R = 10\text{V}$
Reverse recovery time	t_{rr}		3		ns	Switched from $I_F = 500\text{mA}$ to $V_R = 5.5\text{V}$ measured @ $I_R = 50\text{mA}$
Reverse recovery charge	Q_{rr}		210		pC	$di/dt = 500\text{mA/ns}$ $R_{source} = 6\Omega < R_{load} = 10\Omega$

NOTES:

(*) Measured under pulsed conditions. Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.

To (Version 2):

Maximum Ratings @ $T_A = 25^{\circ}\text{C}$ unless otherwise specified

Characteristic	Symbol	Value	Unit
Continuous Reverse Voltage	V_R	10	V
Forward Current	I_F	750	mA
Peak Repetitive Forward Current Rectangular Pulse Duty Cycle 50% 100 μs Pulse Width	I_{FPK}	1.35	A
Non Repetitive Forward Current	I_{FSM}	$t \leq 100\mu\text{s}$	17
		$t \leq 10\text{ms}$	4

Electrical Characteristics @ $T_A = 25^{\circ}\text{C}$ unless otherwise specified

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
Reverse Breakdown Voltage	$V_{(BR)R}$	10	-	-	V	$I_R = 200\mu\text{A}$
Forward Voltage (Note 5)	V_F		285	300	mV	$I_F = 10\text{mA}$
			350	380	mV	$I_F = 100\text{mA}$
			500	580	mV	$I_F = 1\text{A}$
Reverse Current	I_R		0.5	4	μA	$V_R = 5\text{V}$
			0.7	5	μA	$V_R = 8\text{V}$
			1	6	μA	$V_R = 10\text{V}$
			-	200	μA	$V_R = 8\text{V}, T_A = 85^{\circ}\text{C}$
Diode Capacitance	C_D		37		pF	$f = 1\text{MHz}, V_R = 10\text{V}$
Reverse Recovery Time	t_{rr}		3		ns	Switched from $I_F = 500\text{mA}$ to $V_R = 5.5\text{V}$
Reverse Recovery Charge	Q_{rr}		210		pC	Measured @ $I_R = 50\text{mA}$. $di/dt = 500\text{mA/ns}$, $R_{source} = 6\Omega; R_{load} = 10\Omega$

Notes: 5. Measured under pulsed conditions. Pulse width $\leq 300\mu\text{s}$. Duty cycle $< 2\%$

All graphs in version 2 have been updated to reflect revised typical performance.